

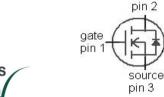
### **OptiMOS**<sup>™</sup>3 Power-Transistor

### **Features**

- N-channel, normal level
- Excellent gate charge x R<sub>DS(on)</sub> product (FOM)
- Very low on-resistance R<sub>DS(on)</sub>
- 175 °C operating temperature
- Pb-free lead plating; RoHS compliant
- Qualified according to JEDEC<sup>1)</sup> for target application
- Ideal for high-frequency switching and synchronous rectification
- Halogen-free according to IEC61249-2-21

### **Product Summary**

$V_{ m DS}$	150	V
$R_{\mathrm{DS(on),max}}$	20	mΩ
$I_{D}$	50	Α



drain





Туре	IPB200N15N3 G	IPD200N15N3 G	IPI200N15N3 G	IPP200N15N3 G
	1 3 2 (tab)	1 2 (tab)	123	123
Package	PG-TO263-3	PG-TO252-3	PG-TO262-3	PG-TO220-3
Marking	200N15N	200N15N	200N15N	200N15N

### **Maximum ratings,** at $T_j$ =25 °C, unless otherwise specified

Parameter	Symbol	Conditions	Value	Unit
Continuous drain current	I <sub>D</sub>	T <sub>C</sub> =25 °C	50	А
		T <sub>C</sub> =100 °C	40	
Pulsed drain current <sup>2)</sup>	I <sub>D,pulse</sub>	T <sub>C</sub> =25 °C	200	
Avalanche energy, single pulse	E <sub>AS</sub>	$I_{\rm D} = 50 \; {\rm A}, \; R_{\rm GS} = 25 \; {\rm \Omega}$	170	mJ
Reverse diode dv/dt	dv/dt	$I_{\rm D}$ =50 A, $V_{\rm DS}$ =120 V, d <i>i</i> /d <i>t</i> =100 A/µs, $T_{\rm j,max}$ =175 °C	6	kV/μs
Gate source voltage	$V_{GS}$		±20	V
Power dissipation	$P_{\text{tot}}$	T <sub>C</sub> =25 °C	150	W
Operating and storage temperature	$T_{\rm j},T_{\rm stg}$		-55 175	°C
IEC climatic category; DIN IEC 68-1			55/175/56	

<sup>1)</sup>J-STD20 and JESD22

<sup>&</sup>lt;sup>2)</sup> See figure 3



# IPB200N15N3 G IPD200N15N3 G IPI200N15N3 G IPP200N15N3 G

Parameter	Symbol	Conditions	Values		Unit	
			min.	typ.	max.	
Thermal characteristics		•				
Thermal resistance, junction - case	$R_{\mathrm{thJC}}$		-	-	1	K/W
Thermal resistance, junction -	$R_{thJA}$	minimal footprint	-	-	75	
ambient		6 cm2 cooling area <sup>3)</sup>	-	-	50	

### **Electrical characteristics,** at $T_i$ =25 °C, unless otherwise specified

### **Static characteristics**

Drain-source breakdown voltage	$V_{(BR)DSS}$	V <sub>GS</sub> =0 V, I <sub>D</sub> =1 mA	150		-	V
Gate threshold voltage	$V_{\rm GS(th)}$	$V_{\rm DS}=V_{\rm GS}, I_{\rm D}=90~\mu{\rm A}$	2	3	4	
Zero gate voltage drain current	I <sub>DSS</sub>	$V_{\rm DS}$ =120 V, $V_{\rm GS}$ =0 V, $T_{\rm j}$ =25 °C	ı	0.1	1	μA
		$V_{\rm DS}$ =120 V, $V_{\rm GS}$ =0 V, $T_{\rm j}$ =125 °C	1	10	100	
Gate-source leakage current	I <sub>GSS</sub>	$V_{\rm GS}$ =20 V, $V_{\rm DS}$ =0 V	ı	1	100	nA
Drain-source on-state resistance	R <sub>DS(on)</sub>	V <sub>GS</sub> =10 V, I <sub>D</sub> =50 A	-	16	20	mΩ
		V <sub>GS</sub> =8 V, I <sub>D</sub> =25 A	-	16	20	
Gate resistance	R <sub>G</sub>		1	2.4	•	Ω
Transconductance	$g_{fs}$	$ V_{\rm DS}  > 2 I_{\rm D} R_{\rm DS(on)max},$ $I_{\rm D} = 50~{\rm A}$	29	57	-	s

 $<sup>^{3)}</sup>$  Device on 40 mm x 40 mm x 1.5 mm epoxy PCB FR4 with 6 cm $^{2}$  (one layer, 70  $\mu$ m thick) copper area for drain connection. PCB is vertical in still air.



# IPB200N15N3 G IPD200N15N3 G IPI200N15N3 G IPP200N15N3 G

Parameter	Symbol	Conditions		Values		Unit
			min.	typ.	max.	
Dynamic characteristics						
Input capacitance	Ciss		-	1820	-	pF
Output capacitance	Coss	$V_{\rm GS}$ =0 V, $V_{\rm DS}$ =75 V, $f$ =1 MHz	-	214	-	
Reverse transfer capacitance	C <sub>rss</sub>	]	-	5	-	
Turn-on delay time	$t_{d(on)}$		-	14	21	ns
Rise time	t <sub>r</sub>	$V_{\rm DD} = 75 \text{ V}, \ V_{\rm GS} = 10 \text{ V},$ $I_{\rm D} = 50 \text{ A}, \ R_{\rm G,ext} = 1.6 \Omega$	-	11	17	
Turn-off delay time	$t_{d(off)}$		-	23	35	1
Fall time	t <sub>f</sub>	]	-	6	9	
Gate Charge Characteristics <sup>4)</sup>						
Gate to source charge	Q <sub>gs</sub>		-	10	14	nC
Gate to drain charge	$Q_{gd}$	],,,, [	-	4	6	
Switching charge	Q <sub>sw</sub>	$V_{DD}$ =75 V, $I_{D}$ =50 A, $V_{GS}$ =0 to 10 V	-	9	13	
Gate charge total	Qg		-	23	31	
Gate plateau voltage	V <sub>plateau</sub>		-	5.7	-	V
Output charge	Q oss	$V_{\rm DD}$ =75 V, $V_{\rm GS}$ =0 V	-	60	79	nC
Reverse Diode	·					
Diode continous forward current	Is	T 25 °C	-	-	50	А
Diode pulse current	I <sub>S,pulse</sub>	- T <sub>C</sub> =25 °C	-	-	220	1
Diode forward voltage	$V_{\mathrm{SD}}$	V <sub>GS</sub> =0 V, I <sub>F</sub> =50 A, T <sub>j</sub> =25 °C	-	1	1.2	V
Reverse recovery time	t <sub>rr</sub>	V <sub>R</sub> =75 V, I <sub>F</sub> =I <sub>S</sub> ,	-	106	-	ns
Reverse recovery charge	Q <sub>rr</sub>	di <sub>F</sub> /dt=100 A/µs	-	332	-	nC

<sup>4)</sup> See figure 16 for gate charge parameter definition

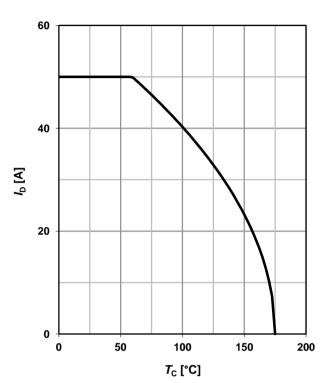


### 1 Power dissipation

### $P_{\text{tot}} = f(T_{\text{C}})$

# 120 120 40 0 50 100 150 200 T<sub>C</sub> [°C]

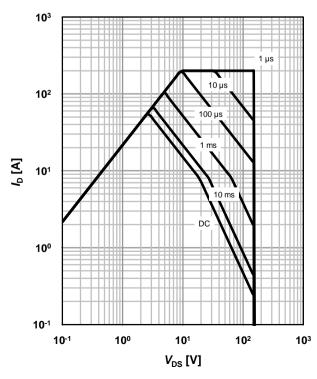
### 2 Drain current



### 3 Safe operating area

 $I_D=f(V_{DS}); T_C=25 \text{ °C}; D=0$ 

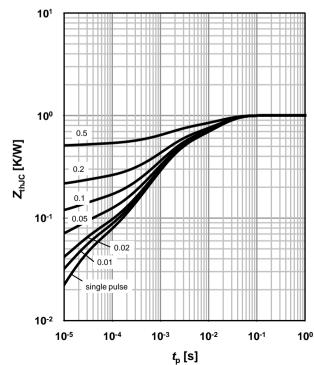
parameter:  $t_p$ 



### 4 Max. transient thermal impedance

 $Z_{\rm thJC}$ =f $(t_{\rm p})$ 

parameter:  $D=t_p/T$ 

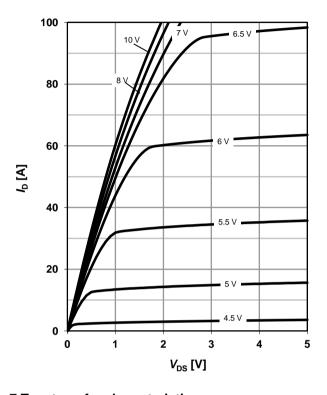




### 5 Typ. output characteristics

 $I_D=f(V_{DS}); T_j=25 °C$ 

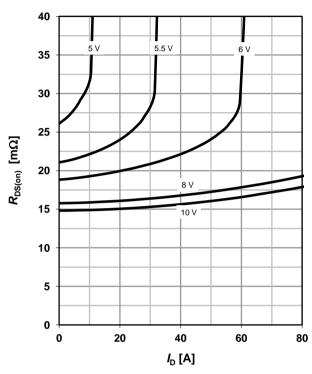
parameter: V<sub>GS</sub>



## 6 Typ. drain-source on resistance

 $R_{DS(on)}=f(I_D); T_j=25 °C$ 

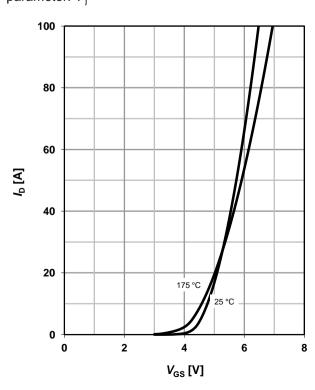
parameter: V<sub>GS</sub>



### 7 Typ. transfer characteristics

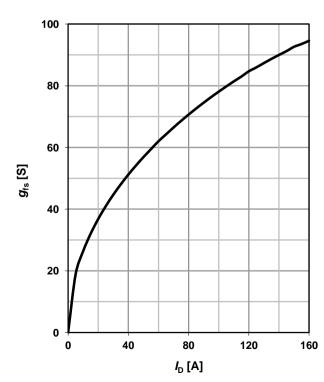
 $I_{D}=f(V_{GS}); |V_{DS}|>2|I_{D}|R_{DS(on)max}$ 

parameter: T<sub>i</sub>



### 8 Typ. forward transconductance

 $g_{fs}$ =f( $I_D$ );  $T_j$ =25 °C





### 9 Drain-source on-state resistance

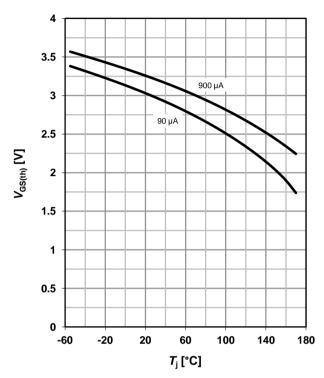
 $R_{DS(on)} = f(T_i); I_D = 50 \text{ A}; V_{GS} = 10 \text{ V}$ 

### 50 45 40 35 $R_{\mathrm{DS(on)}}$ [m $\Omega$ ] 30 25 20 15 10 5 -60 -20 20 60 100 140 180 $T_j$ [°C]

### 10 Typ. gate threshold voltage

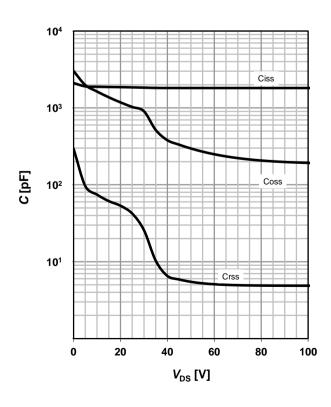
 $V_{GS(th)} = f(T_j); V_{GS} = V_{DS}$ 

parameter: I<sub>D</sub>



### 11 Typ. capacitances

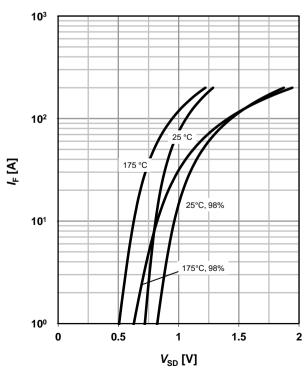
 $C=f(V_{DS}); V_{GS}=0 V; f=1 MHz$ 



### 12 Forward characteristics of reverse diode

 $I_{\mathsf{F}} = \mathsf{f}(V_{\mathsf{SD}})$ 

parameter: T<sub>i</sub>

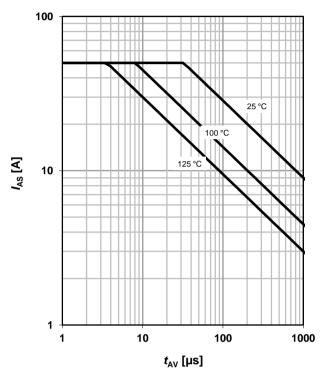




### 13 Avalanche characteristics

 $I_{AS}=f(t_{AV}); R_{GS}=25 \Omega$ 

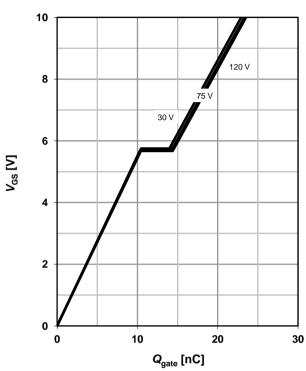
parameter:  $T_{j(start)}$ 



### 14 Typ. gate charge

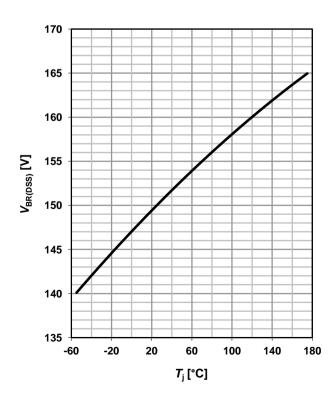
 $V_{GS}$ =f( $Q_{gate}$ );  $I_D$ =50A pulsed

parameter:  $V_{\rm DD}$ 

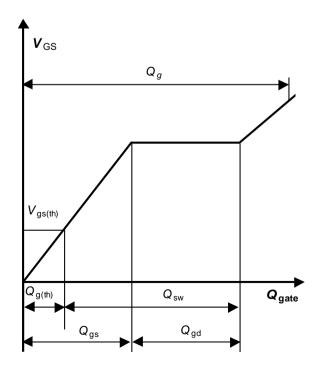


### 15 Drain-source breakdown voltage

 $V_{BR(DSS)}=f(T_j); I_D=1 \text{ mA}$ 

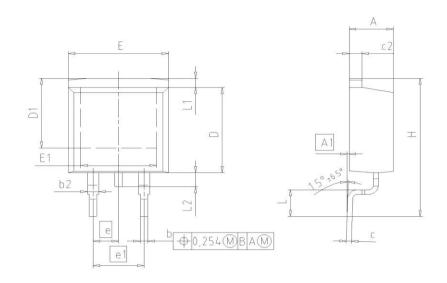


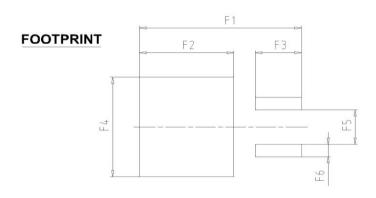
### 16 Gate charge waveforms





### PG-TO263-3 Outline



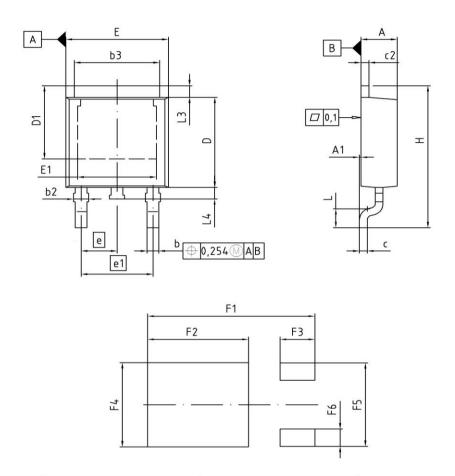


DIM	MILLIM	IETERS	INCI	HES	
DIIVI	MIN	MAX	MIN	MAX	
Α	4.30	4.57	0.169	0.180	
A1	0.00	0.25	0.000	0.010	
b	0.65	0.85	0.026	0.033	
b2	0.95	1.15	0.037	0.045	
С	0.33	0.65	0.013	0.026	
c2	1.17	1.40	0.046	0.055	
D	8.51	9.45	0.335	0.372	
D1	7.10	7.90	0.280	0.311	
E	9.80	10.31	0.386	0.406	
E1	6.50	8.60	0.256	0.339	
е	2.5	2.54		0.100	
e1	5.0	08	0.2	200	
н	14.61	15.88	0.575	0.625	
L	2.29	3.00	0.090	0.118	
L1	0.70	1.60	0.028	0.063	
L2	1.00	1.78	0.039	0.070	
F1	16.05	16.25	0.632	0.640	
F2	9.30	9.50	0.366	0.374	
F3	4.50	4.70	0.177	0.185	
F4	10.70	10.90	0.421	0.429	
F5	3.65	3.85	0.144	0.152	
F6	1.25	1.45	0.049	0.057	

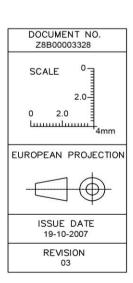
	ENT NO. 003324
SCALE	0
0	5 5 7.5mm
EUROPEAN	PROJECTION
ISSUE 30-08	
REV	ISION



### PG-TO252-3 Outline

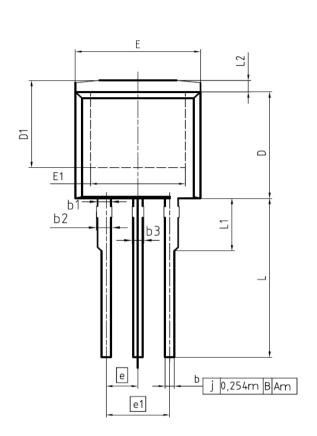


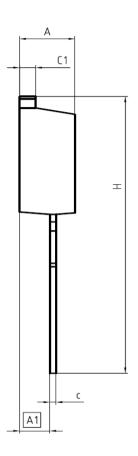
DIM	MILLIM	ETERS	INCH	HES
DIM	MIN	MAX	MIN	MAX
Α	2.16	2.41	0.085	0.095
A1	0.00	0.15	0.000	0.006
Ь	0.64	0.89	0.025	0.035
b2	0.65	1.15	0.026	0.045
ь3	5.00	5.50	0.197	0.217
С	0.46	0.60	0.018	0.024
c2	0.46	0.98	0.018	0.039
D	5.97	6.22	0.235	0.245
D1	5.02	5.84	0.198	0.230
E	6.40	6.73	0.252	0.265
E1	4.70	5.21	0.185	0.205
е	2.	.29	0.090	
e1	4	.57	0.180	
Н	9.40	10.48	0.370	0.413
L	1.18	1.70	0.046	0.067
L3	0.90	1.25	0.035	0.049
L4	0.51	1.00	0.020	0.039
F1	10.50	10.70	0.413	0.421
F2	6.30	6.50	0.248	0.256
F3	2.10	2.30	0.083	0.091
F4	5.70	5.90	0.224	0.232
F5	5.66	5.86	0.223	0.231
F6	1.10	1.30	0.043	0.051





### PG-TO262-3 Outline



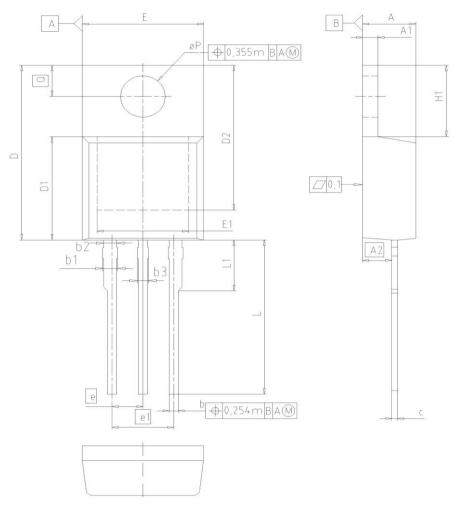


DIM	MILLIMI	MILLIMETERS		HES
DIM	MIN	MAX	MIN	MAX
Α	4.300	4.572	0.169	0.180
A1	2,150	2,718	0.085	0,107
Ь	0.650	0.864	0.026	0.034
b1	0.950	1,093	0.037	0.043
b2	0.950	1.400	0.037	0.055
b3	0.650	1.118	0.026	0.044
С	0.330	0.600	0.013	0.024
c1	1,170	1,400	0.046	0.055
D	8.509	9.450	0.335	0.372
D1	6.900	-	0.272	-
E	9.700	10.363	0.382	0.408
E1	6.500	8.600	0.256	0.339
е	2.5	540	0.100	
e1	5.080		0.2	200
Ĺ	13.000	14.000	0.512	0.551
L1	=	4.800	=	0.189
L2	-	1.727	-	0.068

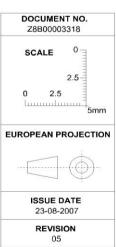
REFERENCE JEDEC TO262
SCALE 0-
0 2.5 5mm
EUROPEAN PROJECTION
ISSUE DATE 05-05-2006
FILE TO262_1



### PG-TO220-3 Outline



DIM	MILLIN	METERS	INC	HES
DIM	MIN	MAX	MIN	MAX
Α	4.30	4.57	0.169	0.180
A1	1.17	1.40	0.046	0.055
A2	2.15	2.72	0.085	0.107
b	0.65	0.86	0.026	0.034
b1	0.95	1.40	0.037	0.055
b2	0.95	1.15	0.037	0.045
b3	0.65	1.15	0.026	0.045
С	0.33	0.60	0.013	0.024
D	14.81	15.95	0.583	0.628
D1	8.51	9.45	0.335	0.372
D2	12.19	13.10	0.480	0.516
E	9.70	10.36	0.382	0.408
E1	6.50	8.60	0.256	0.339
е	2.	54	0.100	
e1	5.	08	0.2	200
H1	5.90	6.90	0.232	0.272
L	13.00	14.00	0.512	0.551
L1	1=	4.80	1-	0.189
øΡ	3.60	3.89	0.142	0.153
Q	2.60	3.00	0.102	0.118





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